Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/673,932	HU, TECK	
Examiner	Art Unit	
Khai M. Nguyen	2687	

SEARCHED				
Class	Subclass	Date	Examiner	
<b>455</b>	414.1 406 408 515 516 518 519	7/12/2005	KN	
370	259 271 229	7/12/2005	KN	
379	157 158	7/12/2005	kn	
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	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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